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International  
Standards



## SEMI® International Standards Program

### ***Compound Semiconductor Technical Committee Meeting***

*Semicon Europa 2019, Neue Messe München, Germany*

*Room: ICM Munich - Room 12b*

**Wed 13<sup>th</sup> November 2019**

**10:00 to 13:00**

V1 02.10.2019

Co-chairs:

- [Dr. Arnd-Dietrich Weber, SiCrystal](#)
- [N.N.](#)

### **Agenda**

#### **European Compound Semiconductor Committee Meeting**

10:00	Welcome and Self-Introductions	all
10:05	SEMI Standards Overview and Legal Reminders	SEMI Staff
10:10	Review of the minutes and action items from the previous meeting	SEMI Staff
10:15	Task Force Reports (~5 minutes each) <ul style="list-style-type: none"> <li>• 5y-review M82</li> <li>• 5y-review M83</li> <li>• SiC-Task Force</li> </ul>	U. Kretzer H.-C. Alt A. Weber
10:30	Ballot review for: <ul style="list-style-type: none"> <li>• SEMI M82 (6474) Test Method for the Carbon Acceptor Concentration in Semi-Insulating Gallium Arsenide Single Crystals by Infrared Absorption Spectroscopy</li> <li>• SEMI M83 (6546) Test Method for Determination of Dislocation Etch Pit Density in Monocrystals of III-V Compound Semiconductors</li> </ul>	all
11:00	New Business: (open discussion) <ul style="list-style-type: none"> <li>• SEMI M55: include spec 200mm SiC wafer diameter</li> </ul>	
11:30	Compound Materials Liaison Reports <ul style="list-style-type: none"> <li>• North America</li> <li>• Japan</li> </ul>	SEMI Staff
11:45	Any Other Business / Questions	A. Weber
12:15	Next Meetings	

12:30	End
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